

White beam X-ray microdiffraction setup on BM32 to study polycrystalline materials with sub-micrometer resolution.

X. Biquard¹, J.S. Micha², F. Rieutord¹, O. Robach¹, O. Ulrich¹

*CEA-Grenoble, DRFMC-SP2M-NRS & CNRS-SPram,
17 rue des Martyrs, F-38054 Grenoble Cedex*

We have recently set-up on BM32 a microdiffraction station that allows one to focus a white beam down to submicron sizes. The setup is dedicated to measurements of orientation and strain in polycrystalline materials. The main characteristics of the setup will be described together with present achievements in terms of beamsize at sample position. A few examples of problems and samples to be addressed with the equipment will be given.